



April 9, 2004

To: Commissioner for Patents
P.O.Box 1450
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572
28 Davis Avenue
Poughkeepsie, N.Y. 12603

Subject: | Serial No. 10/772,939 02/05/04 |

Liang-Gi Yao et al.

A NOVEL DEPOSITION METHOD FOR Si-Ge
EPI LAYER ON DIFFERENT INTERMEDIATE
SUBSTRATES

- INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.

The following Patents and/or Publications are submitted to
comply with the duty of disclosure under CFR 1.97-1.99 and
37 CFR 1.56.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being
deposited with the United States Postal Service as first class
mail in an envelope addressed to: Commissioner for Patents,
P.O. Box 1450, Alexandria, VA 22313-1450, on April 12, 2004.

Stephen B. Ackerman, Reg.# 37761

Signature/Date

 4/12/04

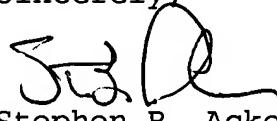
U.S. Patent 6,388,307 to Kondo et al., "Bipolar Transistor," describes a B-doped SiGe layer in a transistor process.

U.S. Patent 5,976,941 to Boles et al., "Ultrahigh Vacuum Deposition of Silicon (Si-Ge) on HMIC Substrates," describes a SiGe epi process.

U.S. Patent 5,273,930 to Steele et al., "Method of Forming a Non-Selective Silicon-Germanium Epitaxial Film," describes a SiGe epi process on a silicon seed layer.

U.S. Patent 5,620,907 to Jalali-Farahani et al., "Method for Making a Heterojunction Bipolar Transistor," describes a method for a heterojunction bipolar transistor.

Sincerely



Stephen B. Ackerman,
Reg. No. 37761

<p>Form PTO-1449</p> <p>O I P INFORMATION DISCLOSURE CITATION IN AN APPLICATION</p> <p>APR 1 5 2004</p> <p>Use several sheets if necessary</p>				Document Number (Optional)	Lightbox Number	
				TSMC-02-029	101772,939	
				Location	Liang - Gi Yao et al.	
				Filing Date	02/05/04	
				Group Art Unit		
U. S. PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILED DATE X APPROXIMATE
	6388307	5/14/02	Kondo et al.	257	592	8/18/99
	5976941	11/2/99	Boles et al.	438	349	6/6/97
	5273930	12/28/93	Steele et al.	437	89	9/3/92
	5620907	4/15/97	Jalali-Farahani et al.	438	320	3/4/96
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES NO
OTHER DOCUMENTS (Including Author, Title, Date, Page, Etc.)						
EXAMINER				DATE CONSIDERED		
<p>EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through</p>						

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